Power MOSFET

30 V, 191 A, Single N-Channel, SO-8FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These are Pb-Free Devices

Applications

- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter		Symbol	Value	Unit	
Drain-to-Source Volt	Drain-to-Source Voltage		V_{DSS}	30	V
Gate-to-Source Voltage		V_{GS}	±20	V	
Continuous Drain		T _A = 25°C	I _D	28	Α
Current R _{θJA} (Note 1)		T _A = 85°C	1	20.5	
Power Dissipation R _{θJA} (Note 1)		T _A = 25°C	P _D	2.7	W
Continuous Drain		T _A = 25°C	I _D	16	Α
Current R _{0JA} (Note 2)	Steady	T _A = 85°C		12	
Power Dissipation R _{θJA} (Note 2)	State	T _A = 25°C	P _D	1.1	W
Continuous Drain		T _C = 25°C	I _D	191	Α
Current R _{θJC} (Note 1)		T _C = 85°C		138	
Power Dissipation R ₀ JC (Note 1)		T _C = 25°C	P _D	113.6	W
Pulsed Drain Current	, ,	= 25°C, = 10 μs	I _{DM}	288	Α
Operating Junction at Temperature	Operating Junction and Storage Temperature		T _J , T _{STG}	-55 to +150	°C
Source Current (Body	Source Current (Body Diode) (Note 3)		I _S	104	Α
Pulse Source Current (Body Diode) (Note 3)		(Body Diode) (Note 3)		312	Α
Drain to Source dV/dt		dV/dt	6	V/ns	
Single Pulse Drain-to-Source Avalanche Energy (T_J = 25°C, V_{DD} = 30 V, V_{GS} = 10 V, I_L = 35 A_{pk} , L = 1.0 mH, R_G = 25 Ω)		EAS	612.5	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)				260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

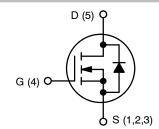
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- Surface-mounted on FR4 board using the minimum recommended pad size (Cu area = 50 mm² [1 oz]).
- 3. Guaranteed by design.



ON Semiconductor®

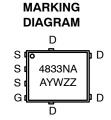
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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	2.0 mΩ @ 10 V	101 A
30 V	3.0 m Ω @ 4.5 V	191 A



N-CHANNEL MOSFET





A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping [†]		
NTMFS4833NAT1G	SO-8FL (Pb-Free)	1500/Tape & Reel		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Тур	Max	Unit	
Junction-to-Case (Drain)	$R_{ heta JC}$	1.0	1.1		
Junction-to-Ambient - Steady State (Note 4)	$R_{ hetaJA}$	43	45.6	°C/W	
Junction-to-Ambient - t < 10s (Note 4)	$R_{ hetaJA}$	16	17.1	C/VV	
Junction-to-Ambient - Steady State (Note 5)	$R_{ heta JA}$	110	117.4		

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size. (Cu area = 50 mm² [1 oz])

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				17		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25 °C			1	
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS}	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 6)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	1.5	1.9	2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				7.12		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V to	I _D = 30 A		1.4	1.9	
		11.5 V	I _D = 15 A		1.4	1.9	_
		V _{GS} = 4.5 V	I _D = 30 A		2.1	2.8	mΩ
			I _D = 15 A		2.1	2.8	
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 15 A			30		S
CHARGES, CAPACITANCES & GATE RESIS	STANCE				•		
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V		2700	5100	7500	pF
Output Capacitance	C _{OSS}			800	1200	1600	
Reverse Transfer Capacitance	C _{RSS}				580	1300	
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$ $V_{GS} = 11.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$		7.4	37	58	nC
Threshold Gate Charge	Q _{G(TH)}				6.0		
Gate-to-Source Charge	Q_{GS}				15	32	
Gate-to-Drain Charge	Q_{GD}			7.0	14	21	
Total Gate Charge	Q _{G(TOT)}			22	86	150	nC
SWITCHING CHARACTERISTICS (Note 7)							
Turn-On Delay Time	t _{d(ON)}			16	23	30	
Rise Time	t _r	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω		15	50	85	ns
Turn-Off Delay Time	t _{d(OFF)}			10	36	32	
Fall Time	t _f				24	71	
Turn-On Delay Time	t _{d(ON)}			8.5	12.5	16.5	
Rise Time	t _r	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω		15	30	45	
Turn-Off Delay Time	t _{d(OFF)}			16	51	86	ns
					1		

Fall Time

6. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
7. Switching characteristics are independent of operating junction temperatures.

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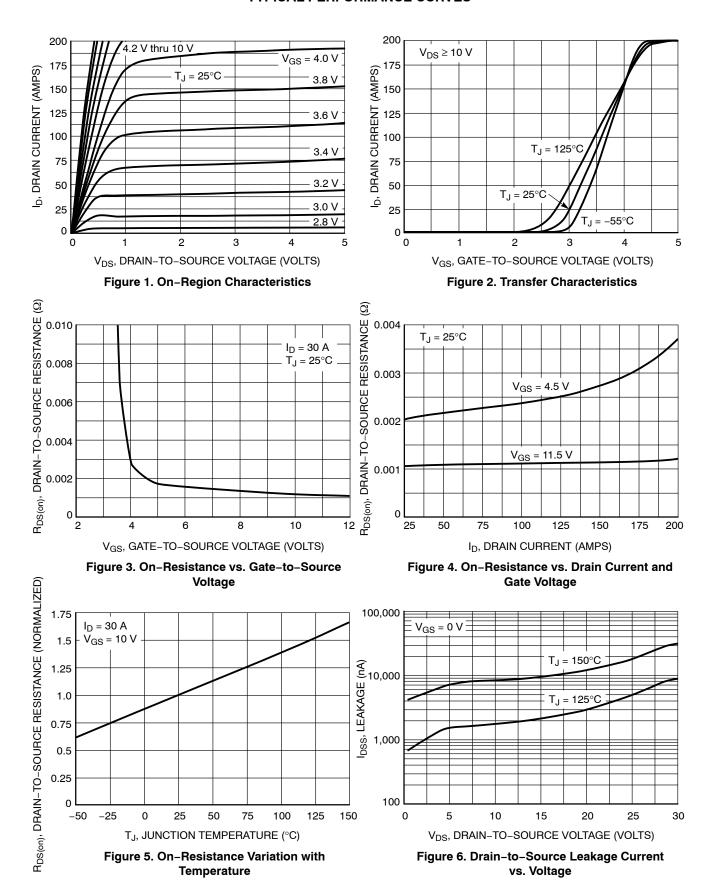
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ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

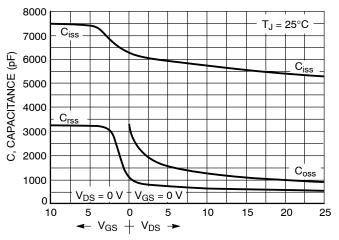
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit		
DRAIN-SOURCE DIODE CHARACTERISTICS									
Forward Diode Voltage	V _{SD}	V_{SD} $V_{GS} = 0 V$	T _J = 25°C		0.8	1.0	V		
		$V_{GS} = 0 \text{ V},$ $I_{S} = 30 \text{ A}$	T _J = 125°C		0.63	0.9	V		
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dIS/dt = 100 A/μs, I _S = 30 A			39	65	ns		
Charge Time	t _a				19				
Discharge Time	t _b				19				
Reverse Recovery Charge	Q _{RR}				36	57	nC		
PACKAGE PARASITIC VALUES									
Source Inductance	L _S	T _A = 25°C			0.50		nΗ		
Drain Inductance	L _D				0.005		nH		
Gate Inductance	L _G				1.84		nΗ		
Gate Resistance	R_{G}				0.6	1.3	Ω		

^{6.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
7. Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES



TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

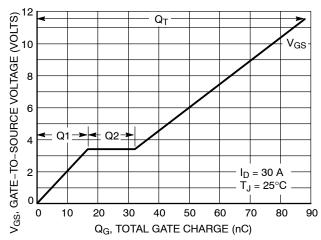


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge



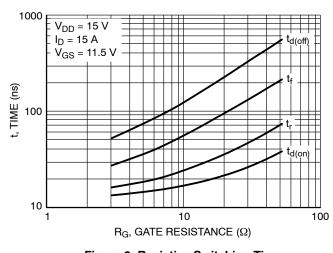


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

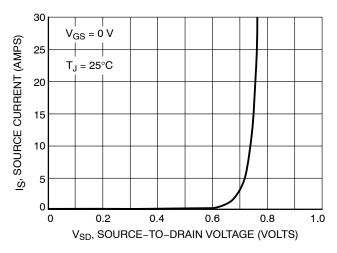


Figure 10. Diode Forward Voltage vs. Current

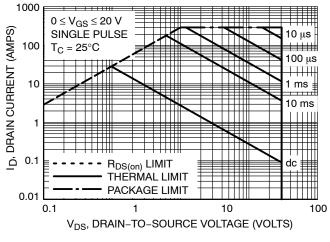


Figure 11. Maximum Rated Forward Biased Safe Operating Area

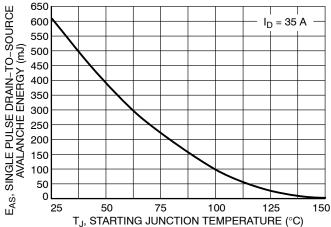


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

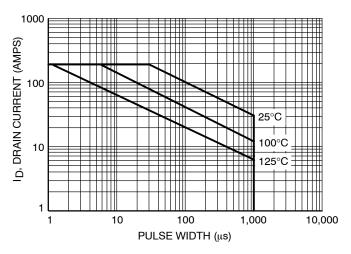


Figure 13. Avalanche Characteristics

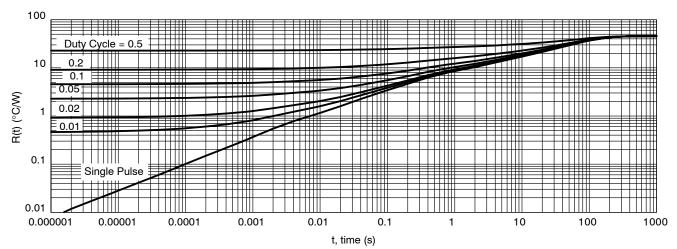
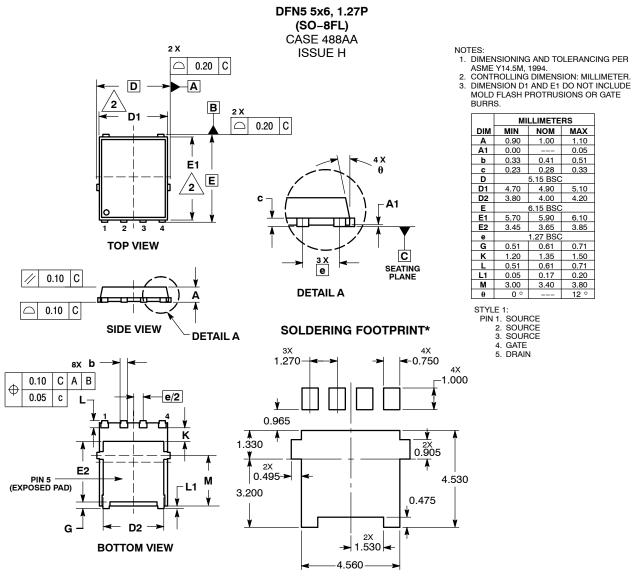


Figure 14. FET Thermal Response

PACKAGE DIMENSIONS



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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